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Increasing Compositional Backscattered Electron Contrast in Scanning Electron Microscopy

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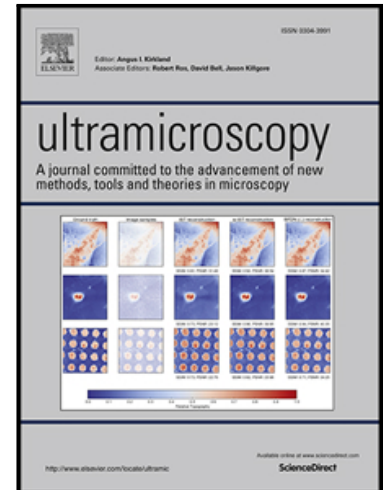
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Highlights

- Compositional contrast of annular backscattered electron detectors is increased.
- The method is based on physical properties of the backscattered electron signal.
- Analytical and semi-empirical algorithms for realizations are provided.
- The proposed method is robust with respect to artifacts.

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